*Electric supporting information for*

# Effect of defect-healing treatment on layered silicate precursors toward well-defined cross-linked frameworks

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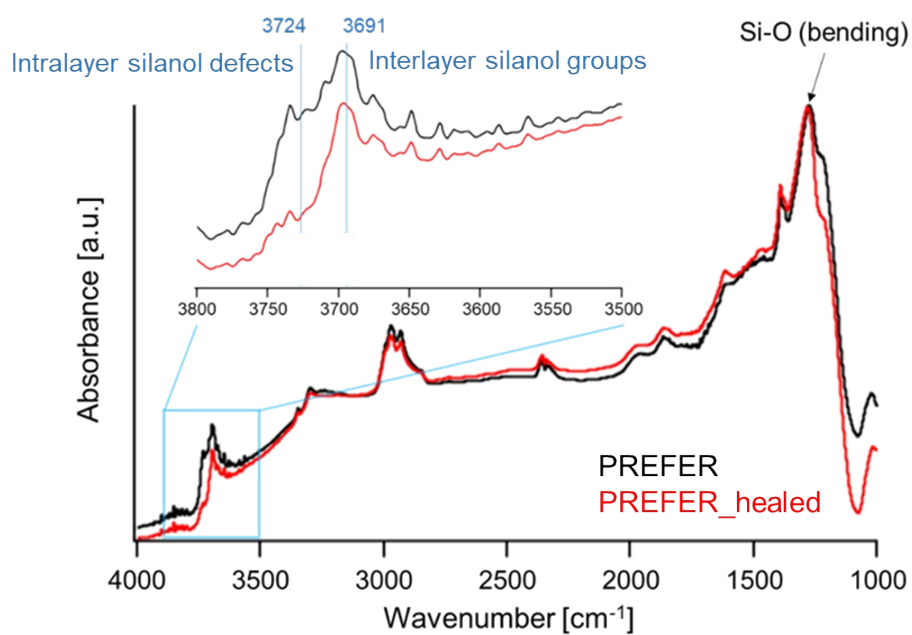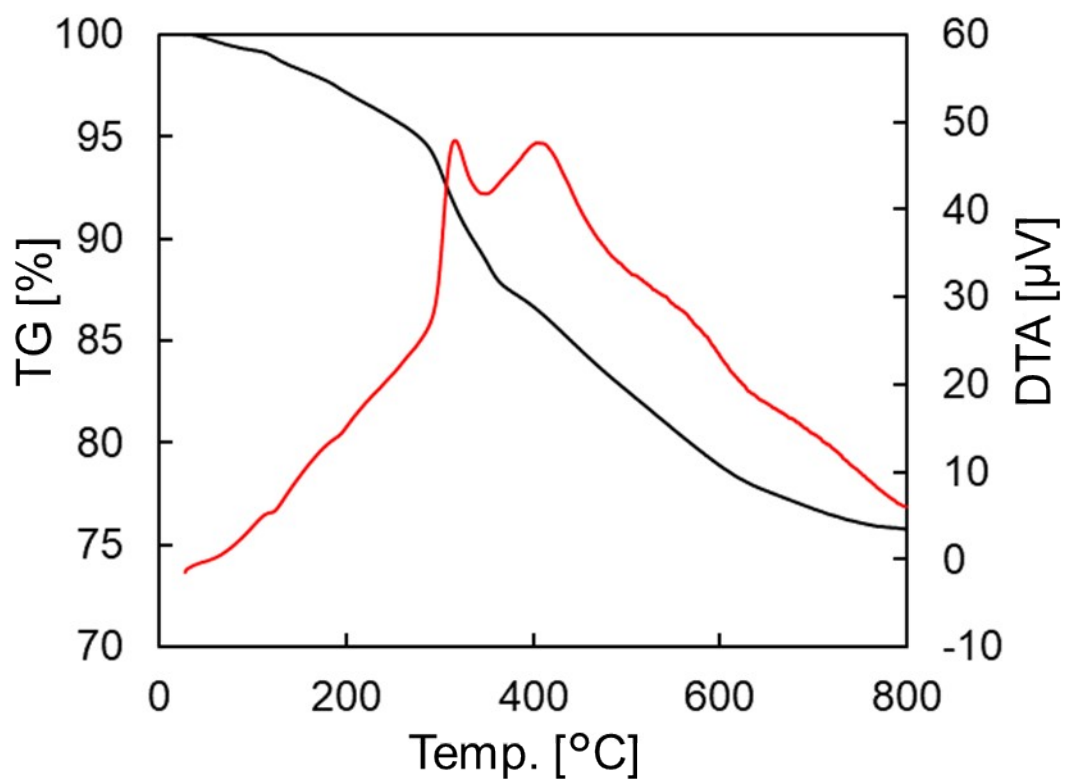
Fig.S1 DRIFT spectra of PREFER and PREFER_healed at 250 °C
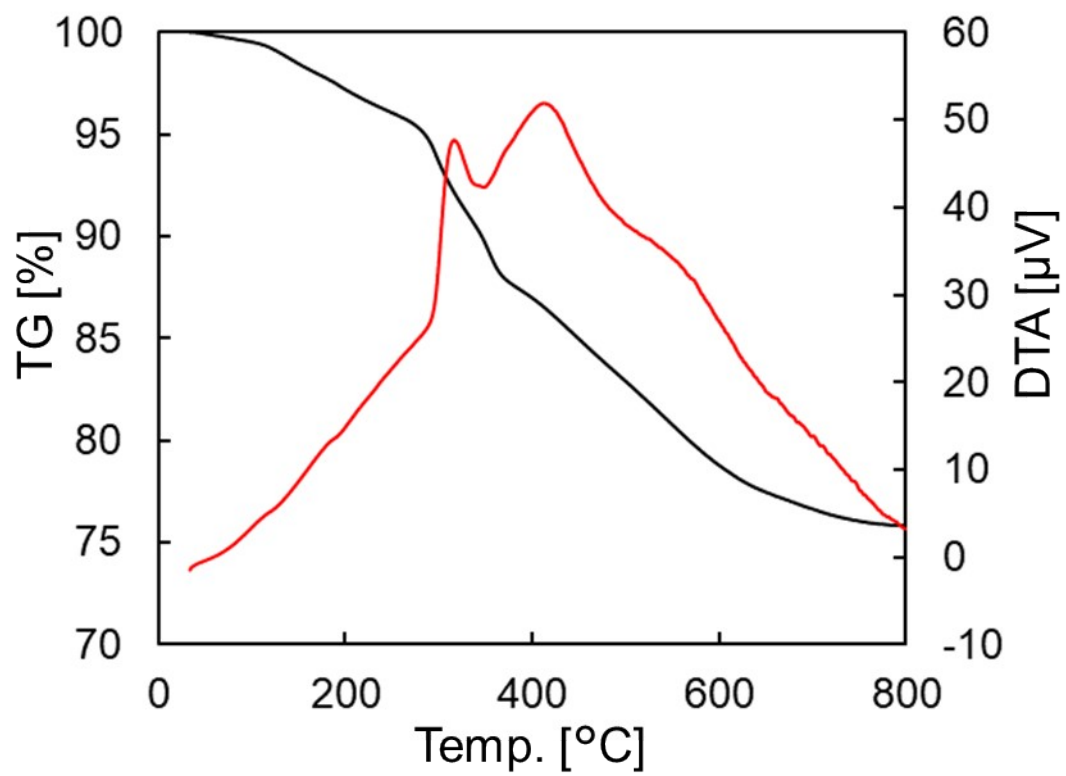


Fig.S2 TG (red) -DTA (black) curves of PREFER

Fig.S3 TG (red) -DTA (black) curves of PREFER_healed
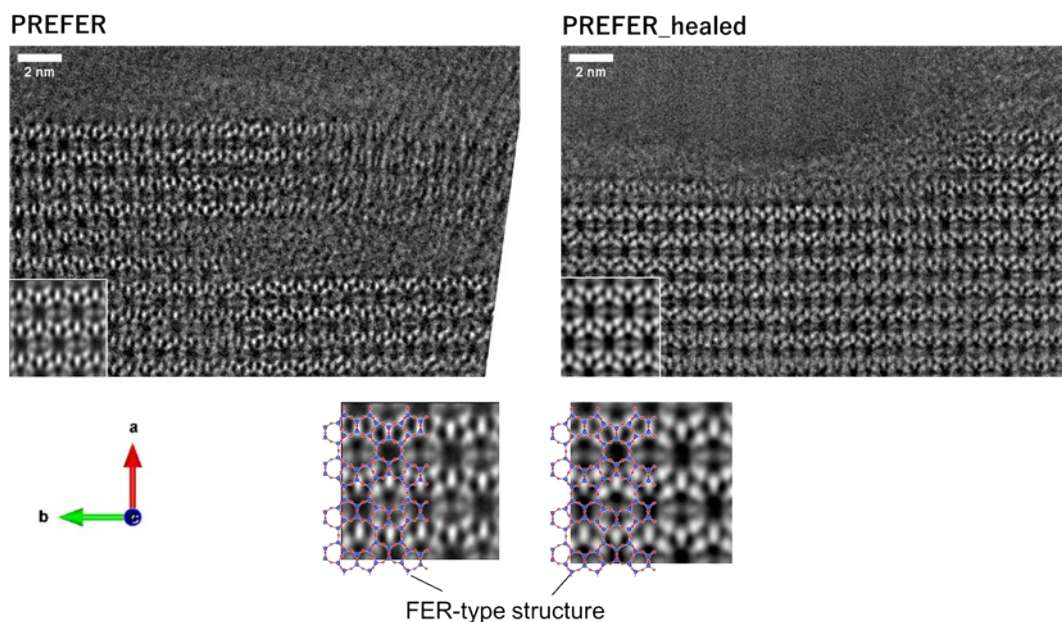


FER-type structure

Fig.S4 TEM image of PREFER and PREFER_healed

Table.S1 CHN Analysis

| Sample | C/N |
|---|---|
| PREFER | 4.77 |
| PREFER_healed | 4.92 |

Table.S2 Si/Fe ratio of samples

| Sample | Si/Fe |
|---|---|
| PREFER_Fe | 193 |
| PREFER_healed_Fe | 121 |